



# **FDP65N06 60V N-Channel MOSFET**

### **Features**

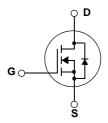
- 65A, 60V,  $R_{DS(on)} = 0.016\Omega @V_{GS} = 10 V$  Low gate charge ( typical 132nC)
- Low Crss (typical 35pF)
- Fast switching
- Improved dv/dt capability

## **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.





## **Absolute Maximum Ratings**

Symbol	Parameter		FDP65N06	Units
V <sub>DSS</sub>	Drain-Source Voltage		60	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		65	А
	- Continuous (T <sub>C</sub> = 100°C)		41	А
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	260	А
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	430	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	65	А
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		13.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		135	W
	- Derate above 25°C		1.08	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

### **Thermal Characteristics**

Symbol	Parameter	FDP65N06	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.92	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W	

# **Package Marking and Ordering Information**

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FDP65N06	FDP65N06	TO-220			50

# **Electrical Characteristics** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	teristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
$\Delta BV_{DSS}/$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C		0.5		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V			1	μА
		V <sub>DS</sub> = 48 V, T <sub>C</sub> = 125°C	-		10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V			-100	nA
On Charact	eristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 32.5 A	-	0.013	0.016	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 32.5 A (Note 4)		39		S
Dynamic Cl	naracteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,		1670	2170	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		464	600	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			35	52	pF
Switching C	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 30 \text{ V}, I_{D} = 65\text{A},$		24	58	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		94	200	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			98	210	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		52	114	ns
Qg	Total Gate Charge	$V_{DS} = 48 \text{ V}, I_{D} = 65\text{A},$		33	43	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		10		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		11		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings	3				
I <sub>S</sub> Maximum Continuous Drain-Source Diode Forward Current					65	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				260	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 65 \text{ A}$			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 65 \text{ A},$		62		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		132		nC

#### NOTES:

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2. L = 47 $\mu$ H, I<sub>AS</sub> =65A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C
- 3.  $I_{SD} \le 65 \text{A}$ , di/dt  $\le 200 \text{A}/\mu \text{s}$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25^{\circ} C$
- 4. Pulse Test : Pulse width  $\leq 300 \mu s, \, \text{Duty cycle} \leq 2\%$
- 5. Essentially independent of operating temperature

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

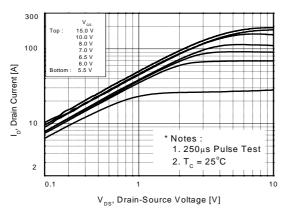


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

Figure 2. Transfer Characteristics

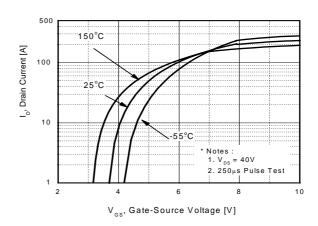
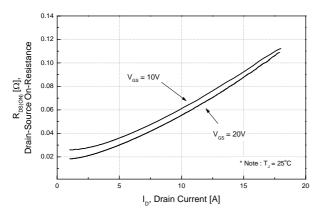


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue



**Figure 5. Capacitance Characteristics** 

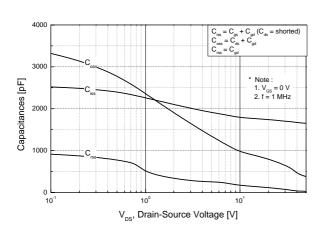
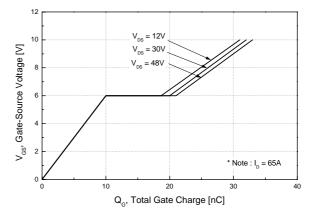


Figure 6. Gate Charge Characteristics



# Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

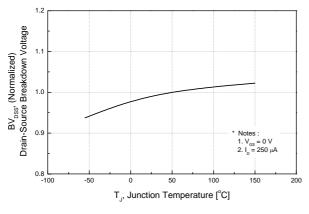


Figure 8. On-Resistance Variation vs. Temperature

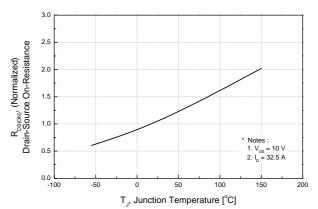
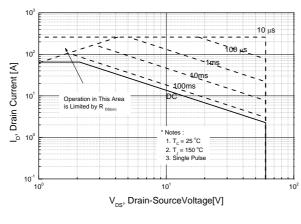


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature



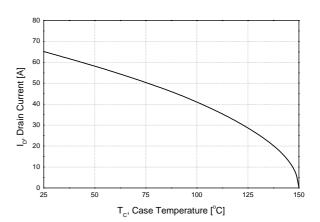
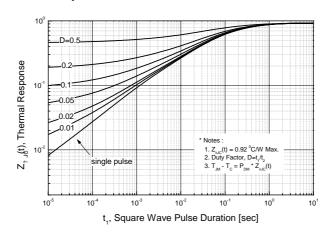
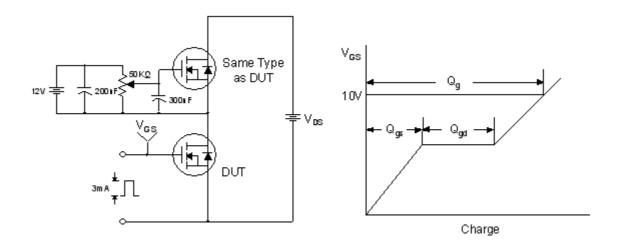


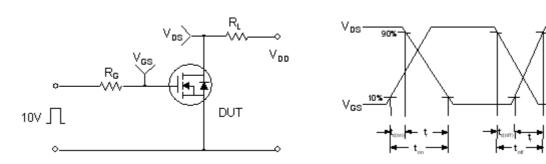
Figure 11. Transient Thermal Response Curve



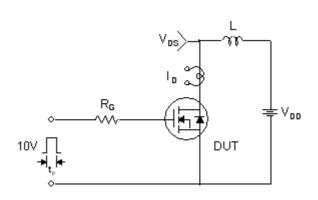
## **Gate Charge Test Circuit & Waveform**

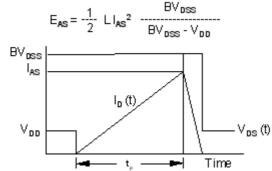


### **Resistive Switching Test Circuit & Waveforms**

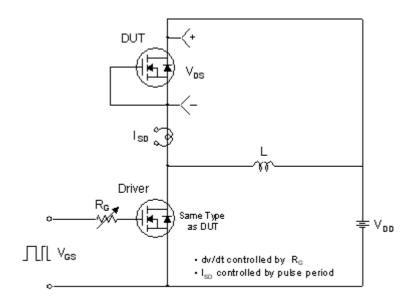


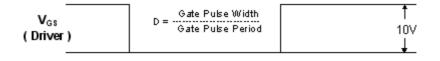
### **Unclamped Inductive Switching Test Circuit & Waveforms**

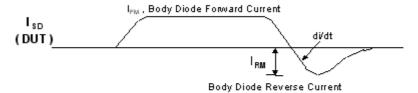


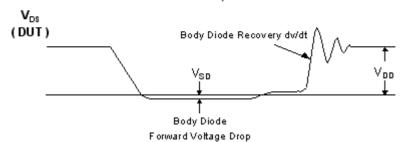


## Peak Diode Recovery dv/dt Test Circuit & Waveforms



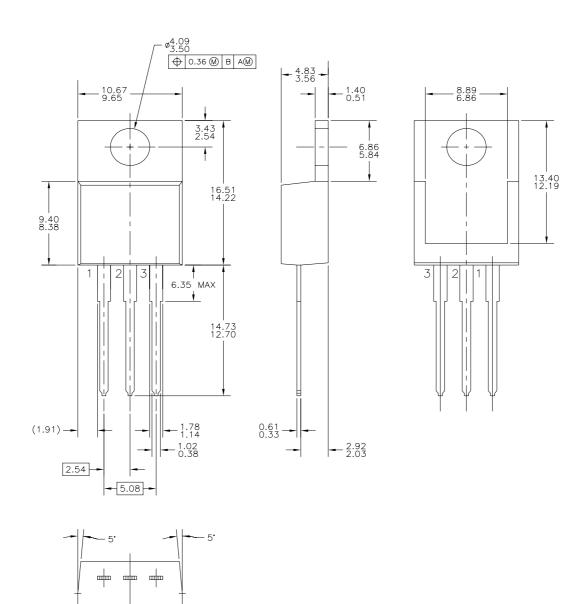






## **Mechanical Dimensions**

# TO-220



**Dimensions in Millimeters** 

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